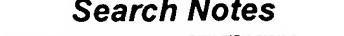


<b>Search Notes</b> 	<b>Application/Control No.</b> 10/516,444	<b>Applicant(s)/Patent under Reexamination</b> WEIST, MARIO
	<b>Examiner</b> PHILIPPE S. DERAKSHANI	<b>Art Unit</b> 3754

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner